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2 WHAT IS CLAIMED IS:

CLAIMS

1. A method for identifying manufacturing anomalies in a manufacturing system comprising a plurality of products which are manufactured with a plurality of manufacturing parameters, the method comprising the steps of:

storing the plurality of manufacturing parameters in a data warehouse;

applying a data mining program to perform the steps of:

analyzing the stored manufacturing parameters to define a first normal manufacturing parameter subset;

detecting at least one of the plurality of manufacturing parameters that is excluded from the first normal subset; and

reporting the at least one detected manufacturing parameter.

- 2. The method of claim 1, wherein the step of applying the data mining program comprises detecting that a plurality of the manufacturing parameters are excluded from the first normal subset.
- 3. The method of claim 2, wherein the step of applying the data mining program further comprises analyzing the detected plurality of manufacturing parameters to define a second normal subset of the detected plurality of manufacturing parameters.
- The method of claim 3, comprising reporting the second normal subset of manufacturing parameters.
- The method of claim 4, wherein the first normal subset of manufacturing parameters is defined by categorizing the manufacturing parameters in an n-dimensional space.

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- 1 6. The method of claim 5, wherein the second normal subset of manufacturing parameters is
- defined by categorizing the manufacturing parameters excluded from the first normal
- subset in the n-dimensional space using the data mining program.

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1	7.	A system for identifying manufacturing anomalies in a manufacturing system comprising
2		a plurality of products which are manufactured with a plurality of manufacturing
3		parameters, comprising:
4		a data warehouse for storing the plurality of manufacturing parameters;

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a data warehouse for storing the plurality of manufacturing parameters;

a data mining program applied to the data warehouse for analyzing the stored manufacturing parameters to define a first normal manufacturing parameter subset and detecting at least one of the plurality of manufacturing parameters that is excluded from the first normal subset; and

a reporting means for reporting the at least one detected manufacturing parameter.

- 8. The system of claim 7, wherein the data mining program is for detecting that a plurality of the manufacturing parameters are excluded from the first subset.
- 9. The system of claim 8, wherein the data mining program is further for analyzing the detected plurality of manufacturing parameters to define a second normal subset of the detected plurality of manufacturing parameters.
- 10. The method of claim 9, wherein the reporting means is for reporting the second normal subset of manufacturing parameters.
- 1 11. The system of claim 10, wherein the data mining program is for defining the first normal subset of manufacturing parameters by categorizing the manufacturing parameters in an n-dimensional space.

- 1 12. The system of claim 11, wherein the data mining program is for defining the second
- 2 normal subset of manufacturing parameters by categorizing the manufacturing
- parameters excluded from the first normal subset in the n-dimensional space.